Advanced Future Communication Techniques and Security Solutions for 6G and Internet of Things

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Deadline for manuscript submissions:
closed (1 July 2023)

Message from the Guest Editors

Dear Colleagues,

In this Special Issue of MDPI's *Electronics*, we look for original and creative contributions that speak across multiple subfields of Advanced Future Communication Techniques for 6G and Internet of Things. Research papers with theoretical and/or practical approaches as well as review papers are all welcome. Topics of interest include, but are not limited to:

- Advanced physical-layer techniques and standards;
- AI-enabled edge computing;
- Reconfigurable intelligent surfaces;
- Terahertz communication techniques for 6G and IoT;
- Unified communication platforms;
- Massive ultra-reliable and low-latency communications;
- 6G-based Vehicular IoT;
- 6G for Industrial IoT;
- Applications of AI in IoT;
- Applications of AI in 6G;
- Applications of 6G and IoT in the medical field;
- Security and privacy in 6G and IoT;
- Network security.

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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